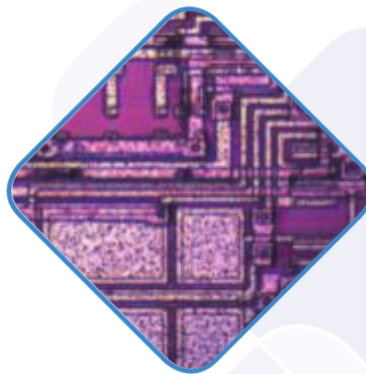


LAB 40 M Series Microscope





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LAB 40 M is a new generation metallographic microscope, based on the LAB 40 model. High quality optics, bright, adjustable reflected and transmitted LED light and the possibility to observe in bright field technique and polarized light make the LAB 40 M a perfect device for metallographic research both in industry and education.

Technical parameters*

Optics	Infinity-corrected optical system.
Viewing head	Binocular or trinocular (optional). Adjustable interpupillary distance: 54-75 mm. Eyepiece inclination: 30°. Dioptric correction: +/- 5 diopters in left eyepiece (binocular viewing head) or in both eyepieces (trinocular viewing head).
Eyepieces	Wide field of view PL10X/22 mm.
Revolving nosepiece	Quintuple.
Objectives	Plan achromatic LWD objectives: 5x, 10x, 20x, 50x, 100x.
Condenser	N.A.0.9 (SWING) condenser.
Focus adjustment	Coaxial coarse and fine focus adjustment knob with coarse focus movement tension adjustment. Movement range: 28 mm. Movement precision: 0,002 mm.
Stage	Double layers mechanical stage with convenient, vertical XY manipulators. Dimensions: 175 x 145 mm. Movement range: 76x42 mm. Max. specimen height: 78 mm (reflected light base) or 28 mm (reflected and transmitted light base). Glass specimen plate for transmitted and reflected light base; metal specimen plate for reflected light base.
Illumination	Reflected light module: warm, adjustable 5W LED light with field and aperture diaphragm. Transmitted light: warm, adjustable 5W LED light.

** Due to constant technological progress, the parameters provided above are purely informational in nature, depict an example configuration and are liable to change*